ADVANCED TECHNIQUES FOR SURFACE CHARACTERIZATION

AFM, MFM and SEM are key nanoscale surface characterization techniques used in different disciplines of science and engineering. The objective of the workshop is to bring experts and interested researchers together. This workshop will be helpful for young researchers for learning basic concepts and applications of the various techniques.

- Sessions will include a series of expert lectures and demonstrations.
- Learn and interact with experts starting from fundamentals to practical.
- Opportunity for expert guidance.

TOPICS
Atomic Force Microscopy (AFM)
Magnetic Force Microscopy (MFM)
Scanning Electron Microscopy (SEM)

REGISTRATION FEE
Research scholars: Rs. 800
Faculty: Rs. 2000
Participants from industry: Rs. 3000
(Registration fee does not include accommodation charges. On request, rooms on payment basis can be arranged in hostels/nearby hotels.)

THAPAR UNIVERSITY
Oct. 28-30, 2015
REGISTRATION Closes
Oct. 16, 2015

REGISTRATION FORM
(Send the registration form with the following details along with a demand draft to the Convener)
1. Name:
2. Position:
3. Organisation:
4. Contact details (Email & Phone number):
5. Demand draft no.:
6. Accommodation required: Yes/No
7. Signature with date

DD should be made in favour of “NWATSC2015” payable at Patiala.

For updates, please visit www.thapar.edu

CONTACT
Dr. M. K. Sharma
Professor & Head
Convener

Dr. S. D. Tiwari
Associate Professor
Secretary

Dr. B. C. Mohanty
Assistant Professor
Joint Secretary

SCHOOL OF PHYSICS & MATERIALS SCIENCE, THAPAR UNIVERSITY, PATIALA - 147004
Email: nwatsc2015@thapar.edu, Phone: 0175 2393893, Fax: 0175 2393005